

### Claim Amendments

Please amend the claims as follows:

1. (Currently Amended)      An integrated circuit having scan test features and including:

a scan test signal interceptor for intercepting scan test related signals applied to the integrated circuit; and

a security element responsive to the scan test signal interceptor to preclude retrieval of secure information within the integrated circuit using the scan test related signals,

wherein the security element comprises:

a reset generator to reset secure information within the integrated circuit.

2. (Cancelled)

3. (Currently Amended)      The integrated circuit of claim [[2]] 1 wherein the scan test signal interceptor is operable to sense a request to enter scan test.

4. (Original)    The integrated circuit of claim 3 wherein the reset generator is operable to reset secure information in response the request to enter scan test.

5. (Currently Amended)      The integrated circuit of claim [[2]] 1 wherein the scan test signal interceptor is operable to sense a request to exit scan test.

6. (Original)    The integrated circuit of claim 5 wherein the reset generator is operable to reset secure information in response the request to exit scan test.

7. (Currently Amended)      A method operable within and tangibly embodied within an integrated circuit to prevent unauthorized access to secure information, the method comprising:

detecting application of a scan test related signal to the integrated circuit; and

precluding access to the secure information in response to detection of the scan test related signal,

wherein the step of precluding includes:

resetting elements of the integrated circuit to reset the secure information.

8. (Cancelled)

9. (Original) The method of claim 7 wherein the step of detecting includes: detecting a signal applied to the integrated circuit requesting entry to scan test.

10. (Original) The method of claim 9 wherein the step of resetting includes: resetting elements of the integrated circuit in response to detection of the request to enter scan test.

11. (Original) The method of claim 9 wherein the step of detecting includes: detecting a signal applied to the integrated circuit requesting exit from scan test.

12. (Original) The method of claim 11 wherein the step of resetting includes: resetting elements of the integrated circuit in response to detection of the request to exit scan test.

13. (Currently Amended) A system including an integrated circuit having a scan test capability, the system comprising:  
means for detecting scan test operation of the integrated circuit; and  
means for precluding retrieval of secure information within the integrated circuit in response to detecting scan test operation,

wherein the means for precluding includes:

reset means for resetting the secure information within the integrated circuit to preclude retrieval thereof using scan test operation.

14. (Cancelled)

15. (Currently Amended) The system of claim ~~[[14]]~~ 13 wherein the reset means is operable to generate a reset within the integrated circuit in response to sensing entry to scan test of the integrated circuit.

16. (Currently Amended) The system of claim ~~[[14]]~~ 13 wherein the reset means is operable to generate a reset within the integrated circuit in response to sensing exit from scan test of the integrated circuit.